



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

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CALIBRATION

Valid To: January 31, 2023

Certificate Number: 1165.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations^{1, 4, 7}:

I. Dimensional

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Gage Blocks – Steel, Ceramic, Carbide, Chrome Carbide Length Parallelism Steel Only: Length Parallelism Length Parallelism	 (0.010 to 4) in (5 to 8) in (10 to 20) in	 (2.3 + 1L) µin 3 µin (3 + 1L) µin 3 µin (10 + 2.7L) µin 3 µin	Gage block comparison
Angle Blocks	Up to 90°	3 in	Sine bar and gage blocks

Parameter/Equipment	Range	CMC ^{2, 5} (\pm)	Comments
Plug Gages – Parallel Plain	(0.007 to 4) in	$(11 + 7L) \mu\text{in}$	ANSI B89.1.5, ULM with gage block
Plug Gages – Taper Diameter Taper Length / Step	Up to 6 in Up to 6 in Up to 6 in	60 μin 90 μin 150 μin	Taper measuring machine Gage block/MuCheck
Pin Gages/Set	Up to 1 in	20 μin	SuperMIC TM , setting disc
Thread Measure Wire	Up to 80 TPI	4 μin	ANSI B89.1.17
Plain Ring Gages – Parallel	(0.04 to 6) in (6 to 12) in	$(7 + 1.5L) \mu\text{in}$ $(15 + 1.5L) \mu\text{in}$	ANSI B89.1.6M ULM/master ring
Plain Ring Gages – Taper Inside Diameter Inside Diameter Taper Length / Step	(0.125 to 4) in Up to 6 in (0.125 to 6) in Up to 4 in	65 μin 110 μin 90 μin 150 μin	ULM – gage block By maser plug By calculation Gage block/MuCheck
Micrometers – Outside ³ ID Rod Type High Resolution	Up to 36 in Up to 24 in Up to 4 in	$(0.6R + 15L) \mu\text{in}$ $(0.6R + 30 + 15L) \mu\text{in}$ 10 μin	By comparison

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Depth Gages ³ – Dial, Digital, Micrometer Types	(1 to 24) in	$(0.6R + 15 + 15L) \mu\text{in}$	By comparison
Squares – Squareness	Length: Up to 18 in	25 $\mu\text{in/in}$	Square checker
Thread Plug Gages – Parallel			
Major Diameter	Up to 16 in	25 $\mu\text{in/in}$	ULM/gage blocks
Simple Pitch Diameter	Up to 4 in (>4 to 12) in	65 μin $(85 + 7L) \mu\text{in}$	3-wire method
Linear Pitch Variation	Up to 16 in	25 $\mu\text{in per 4 in}$	ULM
Flank Angle	Up to 180°	20 arcmin	Optical comparator
Thread Plug Gauge – Taper			
Major Diameter	Up to 6 in	65 μin	Taper measuring instrument
Simple Pitch Diameter	Up to 6 in	170 μin	2 wire/PD measuring
Standoff	Up to 6 in	170 μin	
Taper	Up to 6 in	130 μin	By calculation
Lead	Up to 6 in	25 $\mu\text{in per 4 in}$	
Flank Angle	Up to 180°	20 arcmin	
Step	Up to 4 in	150 μin	Gage block/MuCheck
Thread Ring Gages – Parallel Adjustable Type			
Functional Pitch Diameter	(0.06 to 12) in	$(320 + 15L) \mu\text{in}$	By comparison, fit to master plug
Flank Angle	(5 to 80)°	20 arcmin	By cast method
Minor Diameter	Up to 12 in	70 μin	Bore micrometer/gage block & pins

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Thread Ring Gages – Parallel Non-Adjustable Type			
Simple Pitch Diameter	(0.5 to 6) in	120 µin	By comparison
Lead Variation	(0.5 to 2) in	25 µin per 4 in	
Flank Angle	(5 to 80)°	20 arcmin	By cast method
Minor Diameter	Up to 12 in	70 µin	Bore micrometer /gage block & pins
Thread Ring Gauge – Taper Non-Adjustable			
Simple Pitch Diameter	Up to 4 in	150 µin	ULM/plain ring
Standoff	Up to 6 in	250 µin	Master plug
Taper	Up to 4 in	150 µin	PD measurements
Step/Length	Up to 6 in	150 µin	Gage blocks/MuCheck
Thread Caliper Gauges – Adjustable			
Knife Edge	Up to 12 in	(420 + 5L) µin	Fit to master
Roller Type	Up to 12 in	(250 + 10L) µin	
Vernier, Dial, and Digital Calipers ³	Up to 60 in	(0.6R + 15L) µin	By comparison
Flush Pins – Gages	Up to 6 in	200 µin	Electronic amp, probe, gage blocks
Step Masters	Up to 1 in (>1 to 24) in	20 µin (20 + 6.5L) µin	Electronic amp, probe, gage blocks

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Dial, Digital, and Test Indicators –	Up to 2 in	32 μin	ULM
High-Resolution/Digital	(0.001 to 0.05) in	1.2 μin	Gage blocks
High-Resolution/Analog	Up to 0.1 in	5 μin	
Bore Gages			
2-Point	(0.5 to 24) in	(0.6R + 50) μin	By comparison
3-Point	Up to 6 in	(0.6R + 82 + 10L) μin	Plain setting ring
Length Standards – Setting Rods	(1 to 48) in	(13 + 7L) μin	By comparison
Surface Plates ³ –			
Local Area Flatness	Diagonal: Plates up to 20 ft	9 μin	Fed GGG-P-463c, local flatness variation up to 0.020 in
Overall Flatness	Up to 20 ft	(50 + 4D) μin	D is the length of the diagonal in feet
Optical Comparators ³ –			
Magnification	Up to 100x	800 μin	Opti-master, mag rule, angle blocks, balls
Linearity	Up to 18 in	200 μin	
Angle	Up to 360°	Angle: 2.7 arcmin	
High Resolution Comparators	Up to 2 in	1.5 μin	Master blocks
Height Masters ³	Up to 24 in	(0.6R + 10L) μin	Gage blocks/MuCheck
Digital, Dial, and Vernier Height Gages ³	Up to 48 in	(0.6R + 10L) μin	By comparison
Sine Bars and Plates	Up to 10 in	30 μin/5 in	By comparison

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Precision Levels	Up to 20 in	$(0.6R + 5.5) \mu\text{in}$	Level test rig
Autocollimator	5 in	0.31 arcsec	Gage blocks and sine equipment
Plain Snap Gages ³	Up to 12 in	70 μin	By comparison
Steel Rules	Up to 24 in	0.003 in	Optical comparator
Protractors	Up to 180°	0° 5'	Angle Blocks

II. Dimensional Testing/Calibration¹

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
One Dimensional Measurement ⁶ –			
Diameter	Up to 10 in	70 μin	Bench micrometer
Length	Up to 10 in	70 μin	Bench micrometer
Angle	Up to 180°	0° 3 arcmin	Optical comparator

III. Mechanical

Parameter/Equipment	Range	CMC ² (±)	Comments
Indirect Verification of Rockwell Hardness Testers ³	<p>HRA: Low Medium High</p> <p>HRBW: Low Medium High</p> <p>HRC: Low Medium High</p> <p>HREW: Low Medium High</p> <p>HR15N: Low Medium High</p> <p>HR15TW: Low Medium High</p> <p>HR30N: Low Medium High</p> <p>HR30TW: Low Medium High</p>	<p>0.67 HRA 0.63 HRA 0.63 HRA</p> <p>0.60 HRBW 0.76 HRBW 0.49 HRBW</p> <p>0.65 HRC 0.96 HRC 0.43 HRC</p> <p>0.67 HREW 0.75 HREW 0.56 HREW</p> <p>0.48 HR15N 0.94 HR15N 0.95 HR15N</p> <p>0.61 HR15TW 0.47 HR15TW 0.57 HR15TW</p> <p>0.49 HR30N 0.86 HR30N 0.40 HR30N</p> <p>0.74 HR30TW 0.69 HR30TW 0.50 HR30TW</p>	Indirect verification method per ASTM E18

Parameter/Equipment	Range	CMC ^{2, 5} (±)	Comments
Indirect Verification of Rockwell Hardness Testers ³ – (cont)	HR45N: Low Medium High HR45TW: Low Medium High	0.66 HR45N 0.81 HR45N 0.90 HR45N 1.1 HR45TW 0.73 HR45TW 0.59 HR45TW	Indirect verification method per ASTM E18
Torque Tools ³	450 ft·lbf	1.6 % IV	Torque tester
Torque Testers	5500 in·lbf	0.33 % IV	Standard weights and arms
Force Gauges	Up to 250 lbf	0.1 % IV	By comparison with standard weights
Direct Verification of Durometers (Shore Types A, B, C, D, DO, M, O, and OO) – Indenter Shape and Extension: Diameter Radius Angle Extension Indenter Display Spring Calibration – Force	 Up to 1 in Up to 0.5 in Up to 45° Up to 0.1 in Up to 100 Duro Up to 100 Duro	 200 µin 200 µin 0.8 arcmin 200 µin 200 µin 1.8 % IV	ASTM D2240 Optical comparator Gage blocks Durocalibrator

¹ This laboratory offers commercial dimensional testing/calibration service and field calibration service.

² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

³ Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

⁴ This laboratory offers metric equivalent capability for all items listed.

⁵ In the statement of CMC, L is the numerical value of the nominal length of the device measured in inches; R is the numerical value of the resolution of the device in microinches; D is the numerical value of the nominal diameter of the device measured in inches except where noted; IV is the indicated value.

⁶ This laboratory meets R205 – *Specific Requirements: Calibration Laboratory Accreditation Program* for the types of dimensional tests listed above and is considered equivalent to that of a calibration.

⁷ This scope meets A2LA's P112 *Flexible Scope Policy*.



Accredited Laboratory

A2LA has accredited

FRANK COX METROLOGY

Brampton, ON, CANADA

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 1st day of December 2020.

A blue ink signature of the Vice President of Accreditation Services.

Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 1165.01
Valid to January 31, 2023

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.